



QUALIFICATION REPORT SUMMARY

PCN #: BLAS-09HUWA393

Date:
February 26, 2026

Qualification of palladium-coated copper with gold flash (CuPdAu) as a new bond wire material for selected ATXMEGA128xx, ATXMEGA192xx, ATXMEGA256xx, ATXMEGA32xx, ATXMEGA384xx, and ATXMEGA64xx device families available in 64L and 100L TQFP (14x14x1mm) packages at the MMT assembly site. The AT90CAN128-16AU, AT90CAN128-16AUR, AT90USB1286-AU, AT90USB1286-AUR, AT90USB1287-AU, AT90USB1287-AUR, AT90USB646-AU, AT90USB646-AUR, AT90USB647-AU, AT90USB647-AUR, ATMEGA1280-16AU, ATMEGA1280-16AU-HCM, ATMEGA1280-16AUR, ATMEGA1280V-8AU, ATMEGA1280V-8AUR, ATMEGA1281-16AU, ATMEGA1281-16AUR, ATMEGA1281V-8AU, ATMEGA1281V-8AUR, ATMEGA2560-16AU, ATMEGA2560-16AU-HCM, ATMEGA2560-16AUR, ATMEGA2560V-8AU, ATMEGA2560V-8AUR, ATMEGA2561-16AU, ATMEGA2561-16AUR, ATMEGA2561V-8AU, ATMEGA2561V-8AUR, ATMEGA640-16AU, ATMEGA640-16AUR, ATMEGA640-16AURA0, ATMEGA640V-8AU and ATMEGA640V-8AUR catalog part numbers (CPN) available in 64L and 100L TQFP (14x14x1mm) package assembled at MMT site will qualify by similarity (QBS).

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CCB #: 7411 and 8131

| | | |
|------------|--|-----------------|
| Misc. | Assembly site | MMT |
| | BD Number | BD-004085/01 |
| | MP Code (MPC) | 355E37E5XC03 |
| | Part Number (CPN) | ATMEGA2560-16AU |
| | MSL information | MSL-1 |
| | Assembly Shipping Media (T/R, Tube/Tray) | Tray |
| | Base Quantity Multiple (BQM) | 90 |
| | Reliability Site | MTAI |
| Lead-Frame | Paddle size | 280x280 mils |
| | Material | C7025 |
| | DAP Surface Prep | Bare Cu |
| | Treatment | None |
| | Process | Stamp |
| | Lead-lock (Locking Hole, Half Etched, Dimple, etc. If none, please put No or N/A) | No |
| | Part Number | 10110015 |
| | Lead Plating | Matte Tin |
| | Strip Size | 250.0x70.0mm |
| | Strip Density | 30 pads/strip |
| Bond Wire | Material | CuPdAu |
| Die Attach | Part Number | QMI519 |
| | Conductive | Yes |
| MC | Part Number | G700HA |
| PKG | Package Type | TQFP |
| | Pin/Ball Count | 100 |
| | PKG width/size | 14x14x1mm |



MICROCHIP Package Qualification Report

Manufacturing Information:

| Assembly Lot No. | Wafer Lot No. |
|-------------------|-------------------------|
| MMT-254800100.000 | MCSO525233784.200#24,25 |
| MMT-254800101.000 | MCSO525233784.200#22,23 |
| MMT-254800102.000 | MCSO525233784.200#20,21 |

Pass **Fail** _____

35.9K wafer in 100L TQFP (E5X) with CuPdAu wire at MMT is qualified Moisture/ Reflow Sensitivity Classification Level 1 at 260°C ref low temperature per IPC/JEDEC J-STD-020E standard 1. No delamination observed. HAST, UHAST, TCT and HTSL Passed.

PACKAGE QUALIFICATION REPORT

| Test Number (Reference) | Test Condition | Standard / Method | Qty. (Acc.) | Def/SS | Result | Remarks |
|--|---|-------------------------|----------------|--------|--------|--|
| Precondition Prior Perform Reliability Tests MSL-1 @ 260C | Electrical Test : +85°C, +25°C | JESD22-A113, | 693(0) | | | Good Devices |
| | External Visual Inspection System: Luxo Lamp | JIP/ IPC/JEDE | 693(0) | 0/693 | Pass | |
| | Bake 150°C, 24 hrs System: HERAEUS | | 693(0) | | | |
| | Moisture Soak 85°C/85%RH Moisture Soak 168hrs. System: Climats Excal 5423-HE | | 693(0) | | | |
| | Reflow 3x Convection-Reflow 260°C max System: Mancorp CR.5000F | | 693(0) | 0/693 | | |
| | Electrical Test : +85°C, +25°C | | 693(0) | 0/693 | Pass | |
| Temp Cycle | Stress Condition: (Standard) -65°C to +150°C, 500 Cycles System: VOTSCH VT 7012 S2 | JESD22-A104 | 231(0) | | | Parts had been pre- conditione d at 260°C |
| | Electrical Test: +85°C | | 231(0) | 0/231 | Pass | |
| | Bond Strength: Wire Pull Bond Shear | | 15(0) | 0/15 | Pass | |
| UNBIASED-HAST | Stress Condition: (Standard) +130°C/85%RH, 96H System: HIRAYAMA HASTEST PC-422R8 | JESD22-A118 | 231(0) | | | Parts had been pre- conditione d at 260°C |
| | Electrical Test: +25°C | | 231(0) | 0/231 | Pass | |
| BIASED-HAST | Stress Condition: (Standard) +130°C/85%RH, 96H System: HIRAYAMA HASTEST PC-422R8 | JESD22-A110 | 231(0) | | | Parts had been pre- conditione d at 260°C |
| | Electrical Test: +25°C, +85°C | | 231(0) | 0/231 | Pass | |

PACKAGE QUALIFICATION REPORT

| Test Number (Reference) | Test Condition | Standard/ Method | Qty. (Acc.) | Def/SS. | Result | Remarks |
|---|--|-------------------------------------|-------------------------------|--------------|-------------|---------|
| <p style="text-align: center;">High Temperature Storage Life</p> | <p>Stress Condition: Bake 175°C, 500 hrs System: HERAEUS</p> <p>Electrical Test : +85°C, +25°C</p> | <p>JESD22- A103</p> | <p>150 (0)</p> <p>150 (0)</p> | <p>0/150</p> | <p>Pass</p> | |
| <p>Bond Strength Data Assembly</p> | <p>Wire Pull</p> <p>1 lot, 35 wires from 5 units min</p> | <p>M2011.8 MIL-STD- 883</p> | <p>35(0) Wires</p> | <p>0/35</p> | <p>Pass</p> | |
| <p>Bond Strength Data Assembly</p> | <p>Bond Shear</p> <p>1 lot, 35 bonds from 5 units min</p> | <p>M2011.8 MIL-STD- 883</p> | <p>35(0) bonds</p> | <p>0/35</p> | <p>Pass</p> | |